

Tohoku University, The World Premier International Research Center Advanced Institute for Materials Research (WPI-AIMR), Director of Micro System Integration Center (µSIC)

Experiences of MEMS · IC research and construction of common facility

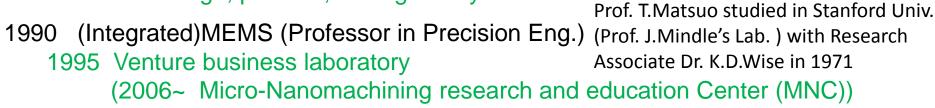
- 1. Chemical sensor & prototyping facility (graduate student) (1970-1975)
- 2. Biomedical micro sensors (Research Associate) (1976-Sept.1981)
- 3. Development of custom CMOS IC (Assoc. Professor) (Oct.1981-1990)
- 4. Integrated MEMS & industrialization (Professor) (1991-)

Open collaboration

- 5. Common facility for prototyping
- 6. Accumulation and utilization of knowledge
- 7. Supporting industry
- 8. Education for students who are eager to be useful

Summary

- 1971 ISFET (Ion Sensitive FET) (Graduate school (Electronic Eng.)) 20mm process facility
- 1976 Medical sensors (Research associate in Electronic Eng.) Common facility for micromachining
- 1981 CMOS LSI (Associate professor in Communication Eng.) LSI design, process, testing facility



2007 Professor in WPI-AIMR (Concurrently in Graduate school of Eng.)
2007 Innovation centers for advanced interdisciplinary research areas program
2008 Closing of Semiconductor Research Institute

(→ J. Nishizawa memorial research and development center in Tohoku Univ.)
2009 Establishment of µSIC
2009 Funding Program for World-Leading Innovative R&D on Science and Tech. (FIRST)
2010 Hands-on access fabrication facility
2013 Retirement from Graduate school of Eng. (Successor : Prof. S.Tanaka)

(2017 Closing of Innovation centers for advanced interdisciplinary research areas program)

WPI-AIMR : The World Premier International Research Center Advanced Institute for Materials Research µSIC : Micro System Integration Center



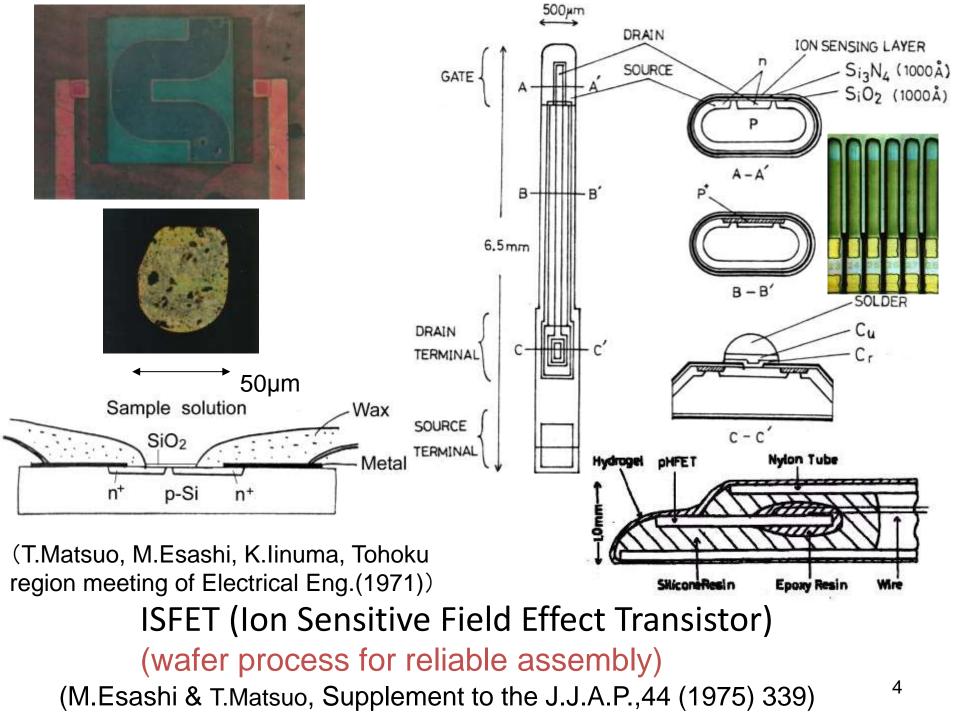


Semiconductor Research Institute (1961~2008)

Prof. emeritus Junich Nishizawa



Nishizawa memorial research center

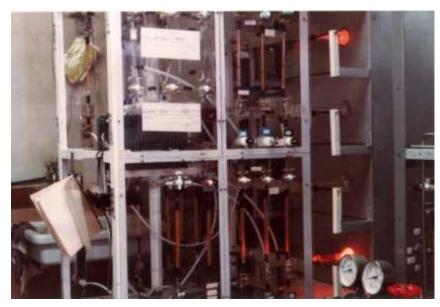




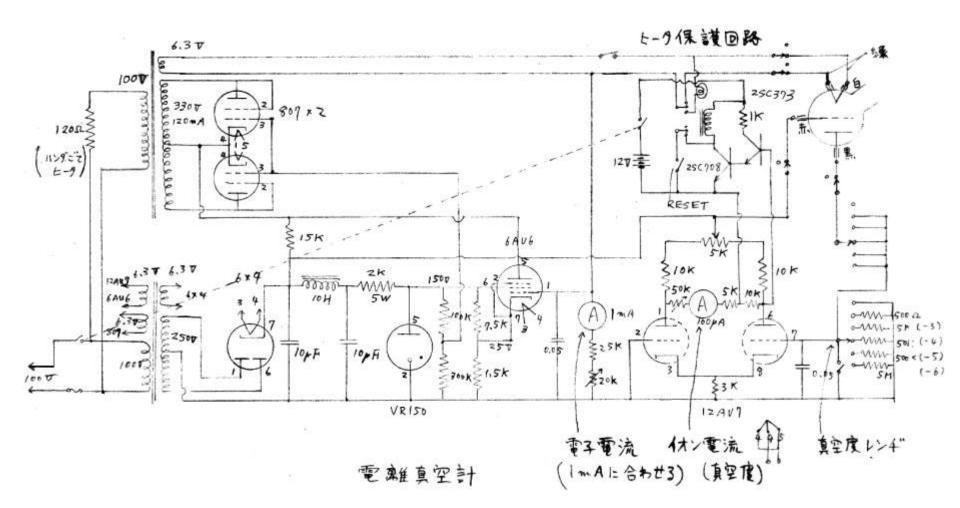


Mask aligner bought by Grant-in-aid for Scientific Research

Double side mask aligner made in house



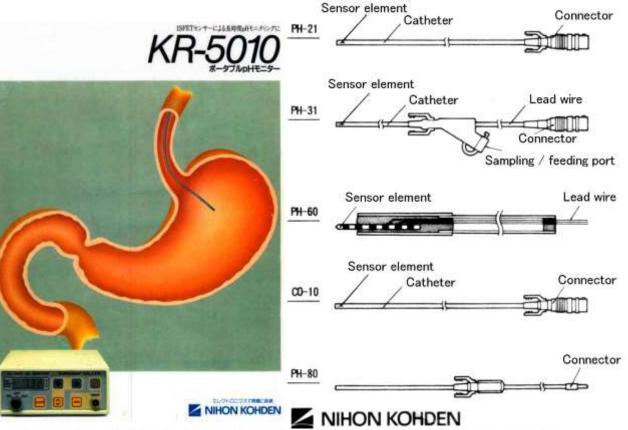




Vacuum measurement system (ionization gage meter) made in house using vacuum tubes



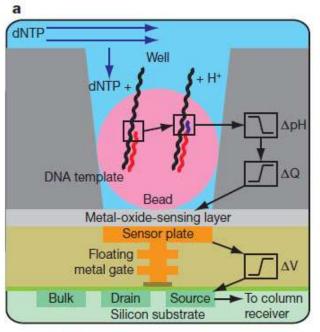
(K. Shimada (Kurare), M. Esashi and T. Matsuo et.al.: Application of catheter-tip I.S.F.E.T. for continuous in vivo measurement, Med. & Biol. Eng. & Comput., Vol.18, No.11, pp.741-745 (1980))

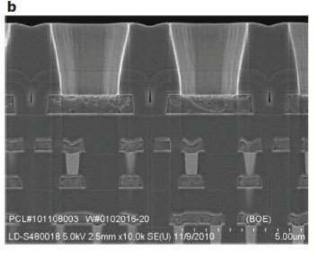


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Туре	Application	No	Catheter (mm)			
			Length	Diameter	Monitor	Note
PH-21	pH measurement in muscle etc	PH-2135	350	1.1	KR-5000	With reference
PH-31	pH measurement in esophagus and stomach	PH-3110 (Adult)	1000	2.4	KR-5000	With reference
		PH-3165 (Infant)	650	2.4	KR-5010	and feed port
PH-60	pH measurement in mouth	PH-6010	100	1.0	KR-5000	Without reference
PH-80	Reference electrode for PH-60	PH-8005	50	1.1	KR-5000	
CO-10	PCO ₂ measurement in muscle etc	CO-1035	350	0.9	KR-5000	With reference

Catheter pH, PCO₂ monitor (Kurare, Nihon Kohden) (1980)





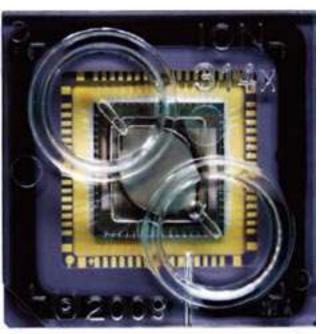


Figure 1 | Sensor, well and chip architecture. a, A simplified drawing of a well, a bead containing DNA template, and the underlying sensor and electronics. Protons (H⁺) are released when nucleotides (dNTP) are incorporated on the growing DNA strands, changing the pH of the well (Δ pH). This induces a change in surface potential of the metal-oxide-sensing layer, and a change in potential (Δ V) of the source terminal of the underlying field-effect

transistor. b, Electron micrograph showing alignment of the wells over the ISFET metal sensor plate and the underlying electronic layers. c, Sensors are arranged in a two-dimensional array. A row select register enables one row of sensors at a time, causing each sensor to drive its source voltage onto a column. A column select register selects one of the columns for output to external electronics.



Small fragment of single strand DNA attached in beads in each well generates hydrogen ion during binding with nucleotides (A-T, G-C) and double strand DNA is synthesized. The pH change is measured by changing a nucleotide solution.

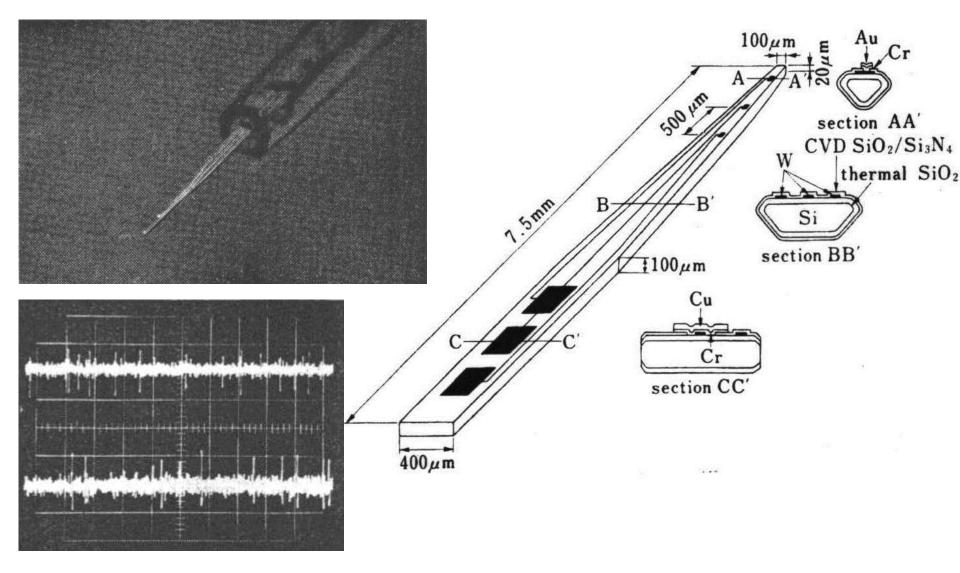
3 chips all DNA sequencer using 165 million ISFETs on a chip

(J.M.Rothberg (Ion Torrent Life Technologies) et al. : An integrated semiconductor device enabling non-optical genome sequencing,, Nature, 475 (2011/7/21) pp.348-352) ⁸

Experiences of MEMS • IC research and construction of common facility

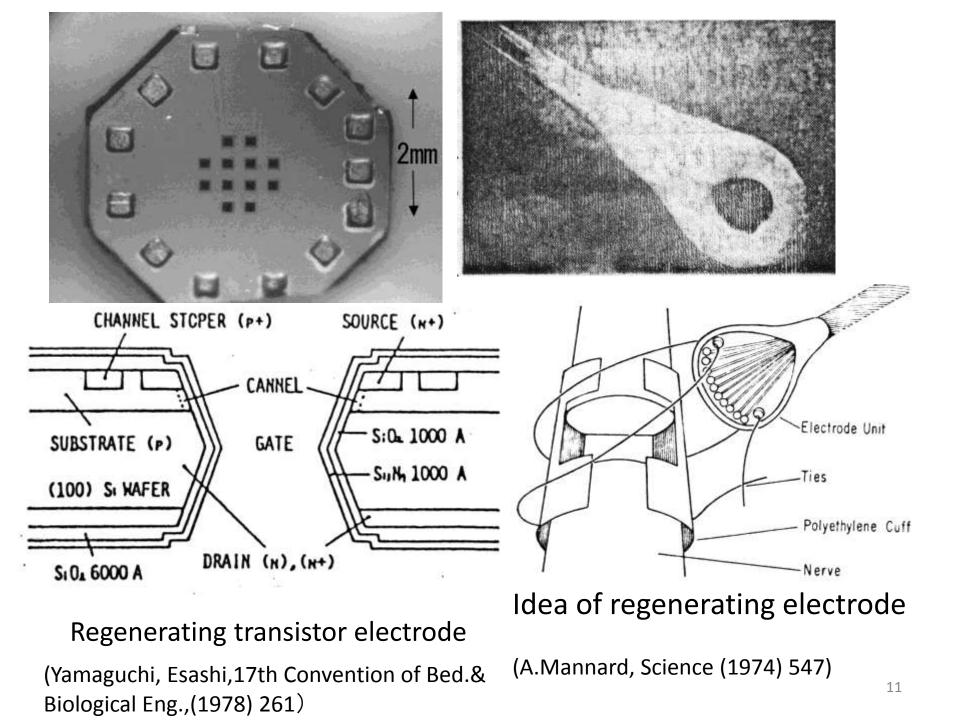
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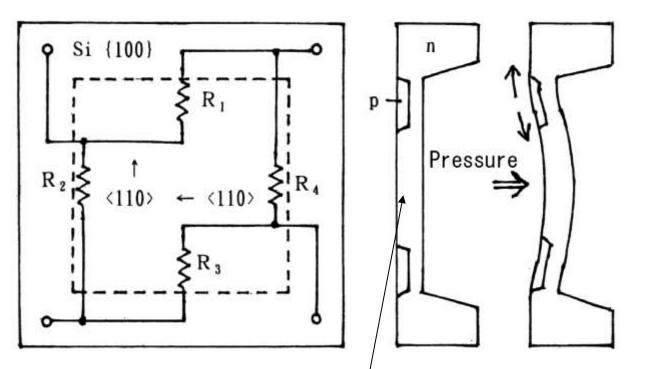
Multi-micro electrode to detect nerve impulse

(Y.Ohta, M.Esashi, T.Matsuo, Medical and Biological Eng., 19, 2 (1981) p.106)





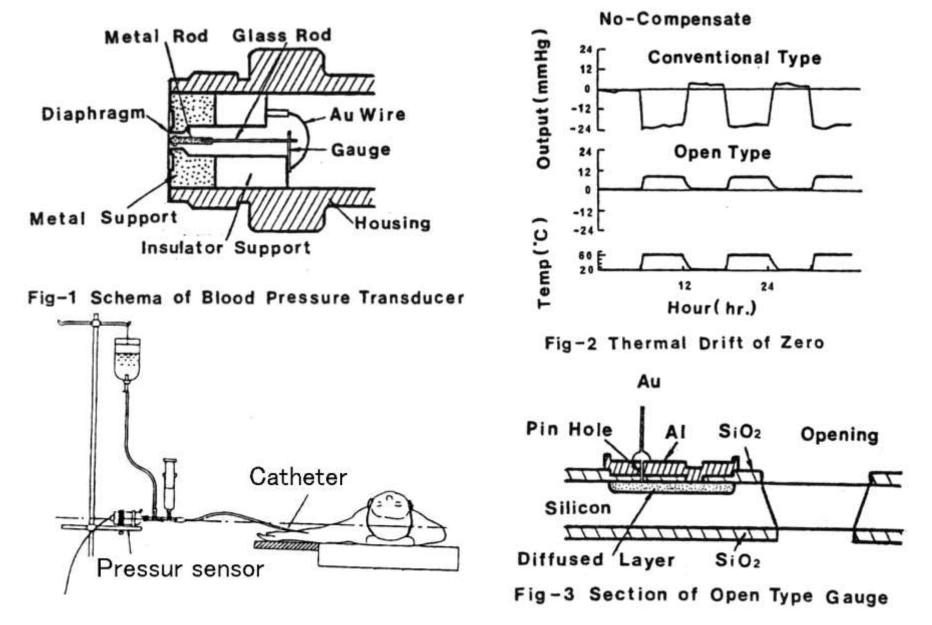
Dr. I. Igarashi (Toyota central research lab.)



Silicon diaphragm with piezoresistors

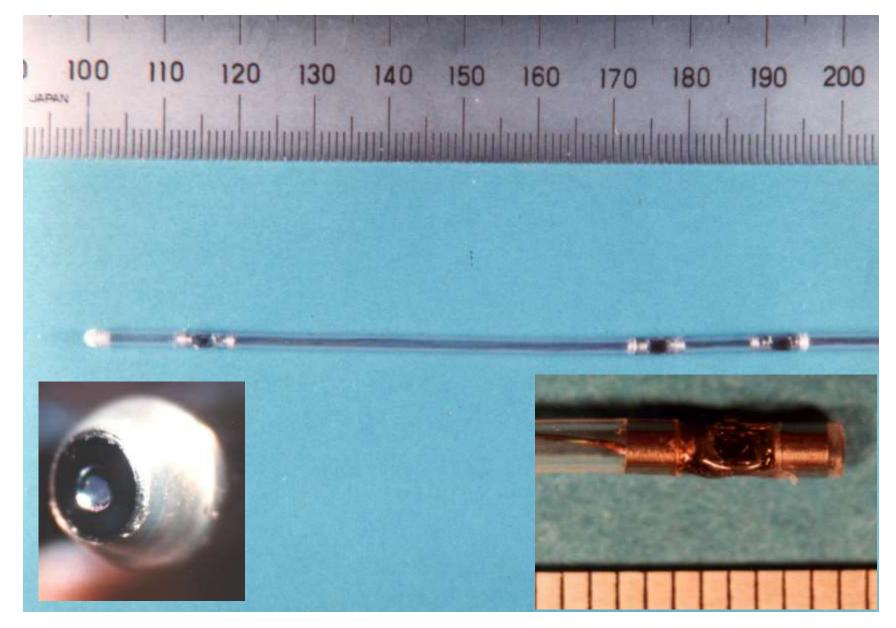
1954 Piezoresistive effect of Si & Ge C.S.Smith (Bell Lab.), (Phy.Rev. 94 (1954) 42)
1963 Silicon diaphragm piezoresistive pressure sensor O.N.Tufte (Honeywell), J.of Applied Physics, 33 (1962) 3322), I.Igarashi (T.C.R.L.)

1980's Commercialized for engine control to reduce exhaust gas pollution **Piezoresistive pressure sensor**¹²

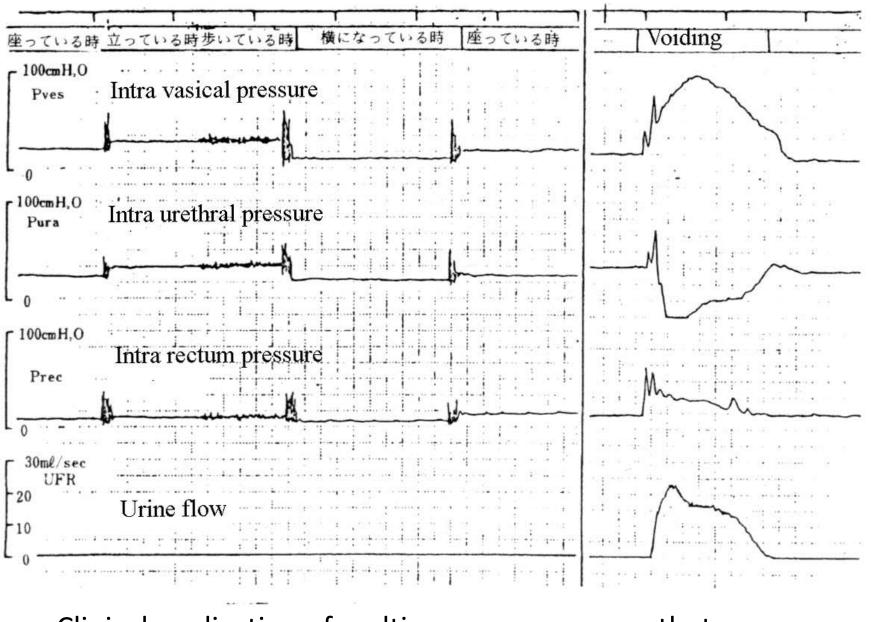


External blood pressure sensor using catheter

(H.Ozawa, M.Esashi, Med.& Biological Eng., 24(special issue) (1986))



Multi piezoresistive pressure sensor catheter (M.Esashi et.al.: IEEE Trans. on Electron Devices, ED29, (1982) 57)

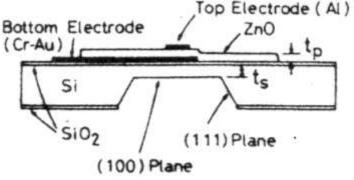


Clinical application of multi-pressure sensor catheter (M.Esashi et.al.: IEEE Trans. on Electron Devices, ED29, (1982) 57)

Proceedings of 1st Symposium on Ultrasonic Electronics, Tokyo, 1980 Japanese Journal of Applied Physics, Vol. 20 (1981) Supplement 20-3, pp. 111-114

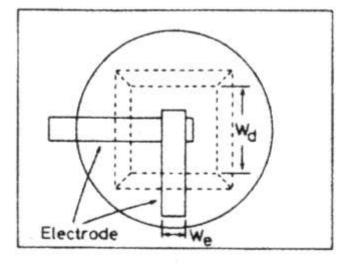
A Piezoelectric Composite Resonator Consisting of a ZnO Film on an Anisotropically Etched Silicon Substrate

Kiyoshi NAKAMURA, Hiromasa SASAKI and Hiroshi SHIMIZU



ctrode (AI) ingineering, Tohoku University, Sendai 980

and Dr. J. Kushibiki for their valuable suggestions on ZnO deposition, and Dr. M. Esashi for his helpful advice on anisotropic etching. They also wish to thank Mr. H. Watanabe and Mr. M. Uriuhara for their technical contributions.



First Film Bulk Acoustic Resonator (FBAR) (1980)

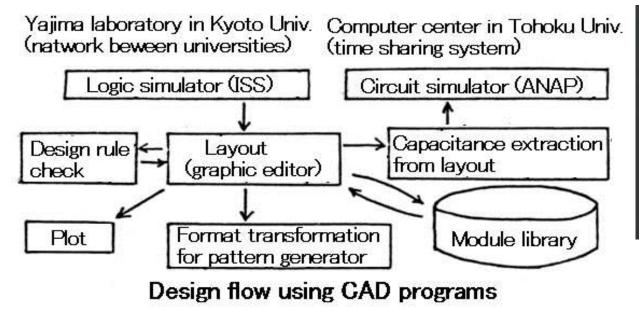
その年の4月に会社に戻り、8月にはもうFET その年の4月に会社に戻り、8月にはもうFET で組み立てる。それを見よう見真似で自分で組み ってたのがよかった。装置を購入していたら、そ れだけで納入まで半年はかかっていたでしょうか らね。そんなこんなで、旧センサまではできたの ですが、その他にナトリウムやカリウムや塩素の したプロセスがベースとなってオリンパスの半導 体技術ができあがっていきました。江刺先生は す	
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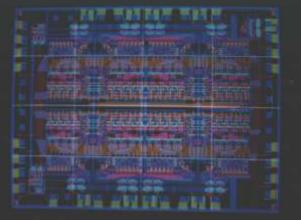
Training of dispatched researchers who have experiences of all the process steps (Olympus)

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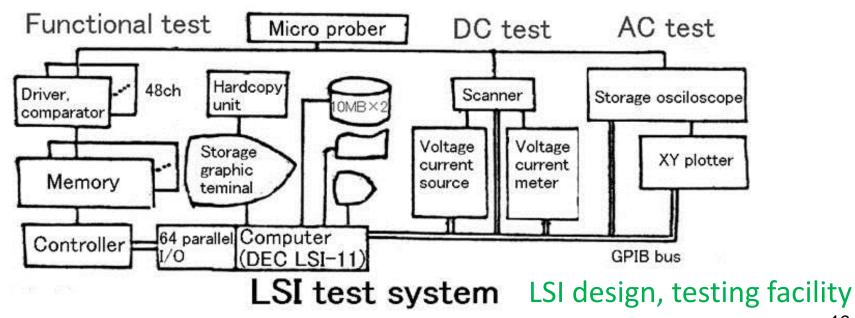
Summary



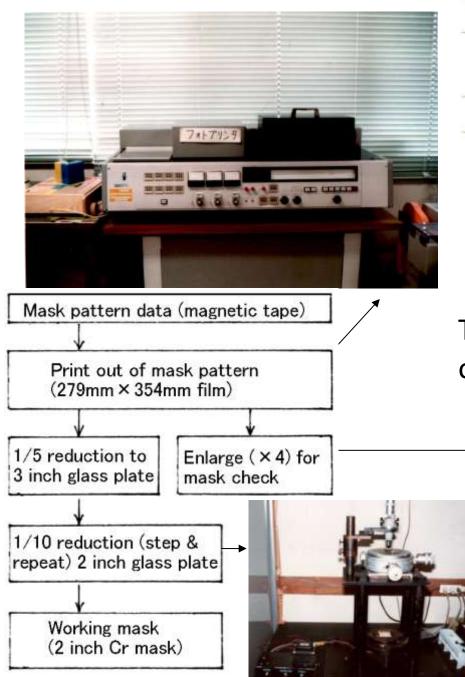


Graphic editor programed by Esashi

(M.Esashi, Experiences of LSI design, prototyping and education, Convention of IEEJ (1984))



(M.Esashi & M.Ohtomo, Fabrication of functional tester for LSI, Tohoku convention of IEEJ (1984))

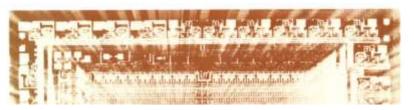


半導体工学シリーズ 🖸

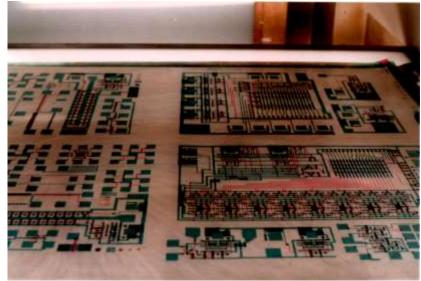
半導体集積回路設計の基礎

西澤潤一編 江剌正喜著

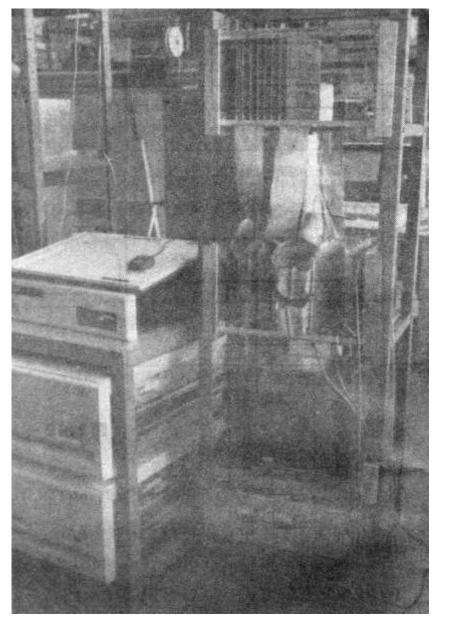
培風館

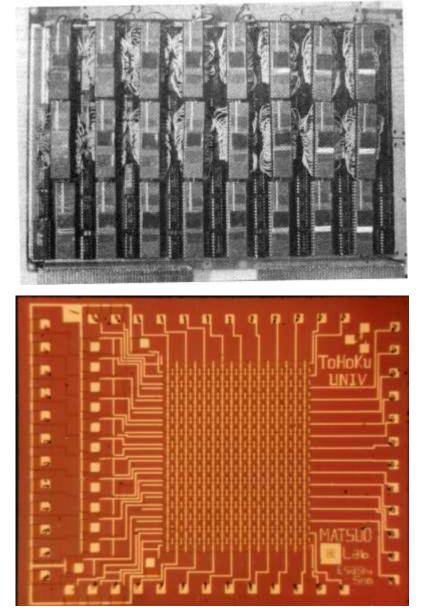


Text book, M.Esashi "Fundamentals of integrated circuit design" (1986)



Mask making process

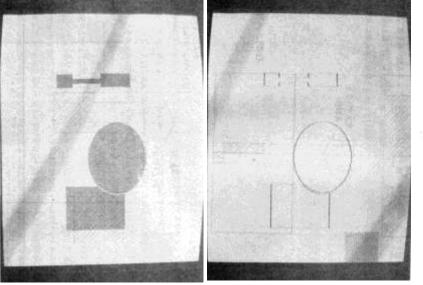




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Parallel image processor using custom made IC for 2D barrel shifter

(M.Esashi et.al., Technical report on semiconductor and transistor, IEC,SSD85-51, (1985))



 Horizontal range:
 Vertical range

 Juput stream
 - 2v/div

 *1
 - 5v/div

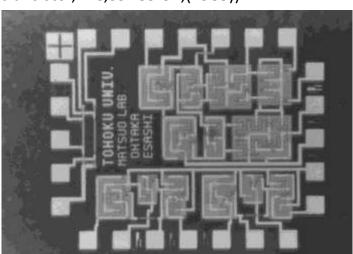
 *2
 - 5v/div

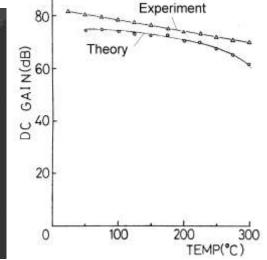
 0ut 1
 - 2v/div

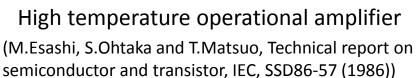
 0ut 2
 - 2v/div

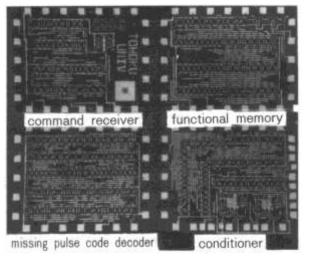
 0ut 3
 - 2v/div

Example of parallel image processing (M.Esashi et.al., Technical report on semiconductor and transistor, IEC,SSD85-51,(1985)) NMOS pipelined image processor using quaternary logic (M.Kameyama, T.Haniyu, M.Esashi and T.Higuchi, ISSCC (1985) 86)









Implantable telemetry CMOSIC (H.Seo, M.Esashi and T.Matsuo, Frontiers of Medical and Biological Engineering, 1 (1989) 319) 22



20mm process facility for LSI and MEMS (1995)

Second-hand ion implanter used in Tokyo Sanyo Ltd

Experiences of MEMS IC research and construction of common facility

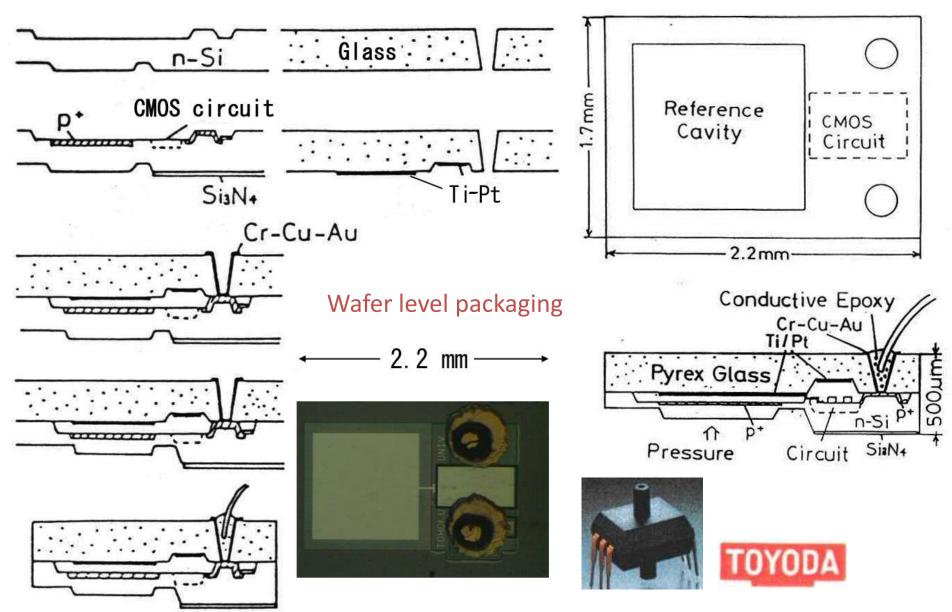
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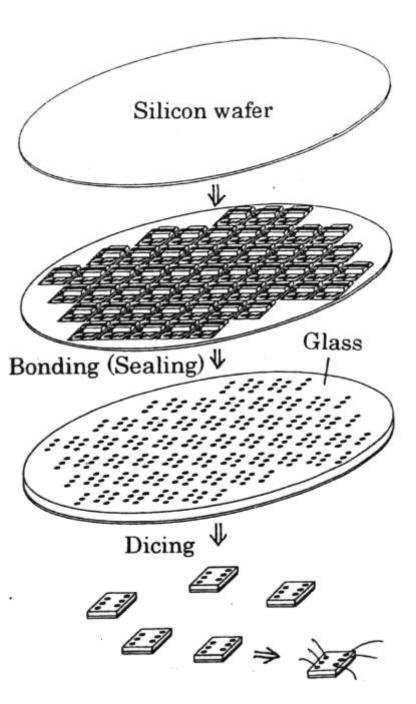
Unique facility like toy for MEMS prototyping

MEMS process facility for 20 mm wafer Many process equipments have been made in house. Simple and basic equipments are suitable for training people who have experiences of all the process and for developing new devices taking advantages of process flexibility. The facility has been shared by many laboratories. More than 100 companies dispatched researchers (full time, 2years).



Integrated capacitive pressure sensor

(Y.Matsumoto, S.Shoji, M.Esashi, 22nd Conf. on Solid State Devices and Materials (1990) 701)



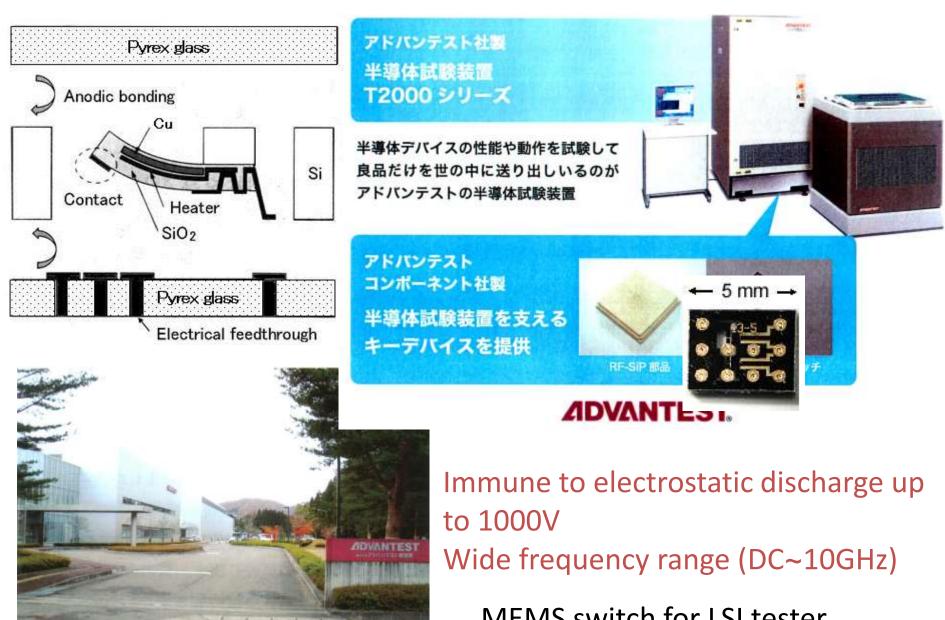
MEMS have moving parts

- → Direct molding with plastics can not be done.
- → small size (chip size encapsulation, suitable for surface mounting)
 → high yield (protection of MEMS structures during dicing)
- \rightarrow high reliability (hermetic sealing)
- \rightarrow low cost (minimal investment for

assembly, no use of expensive

ceramic packages etc)





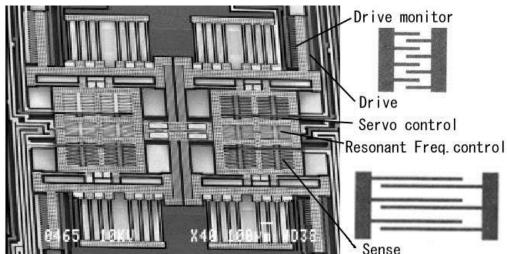
MEMS switch factory (Advantest components (Sendai)) MEMS switch for LSI tester (A.Nakamura et.al., Advantest Technical

Report, 22 (2004), 9-16)

TOYOTA

半導体式ヨーレートセンサーを搭載したクラウン(2003年12月発売)

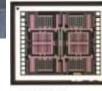




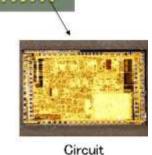
1992-1997

Two researchers from Toyota stayed in Tohoku University for collaborative development of vibrating gyroscope

Yaw rate sensor has been produced in Toyota since 2003 and used in more than 1 million cars.



40.i.m

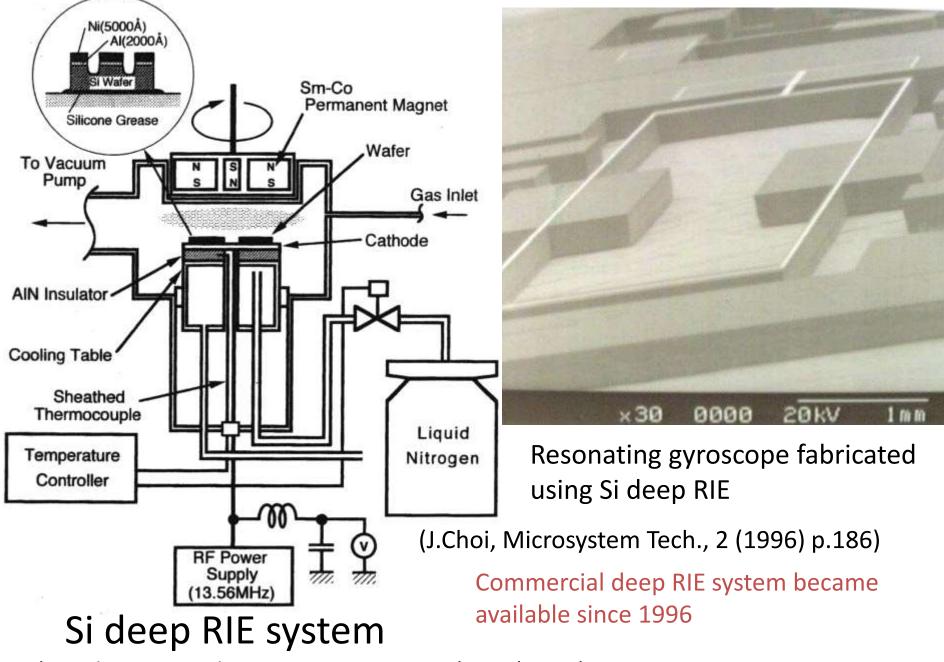


MEMS Sensor

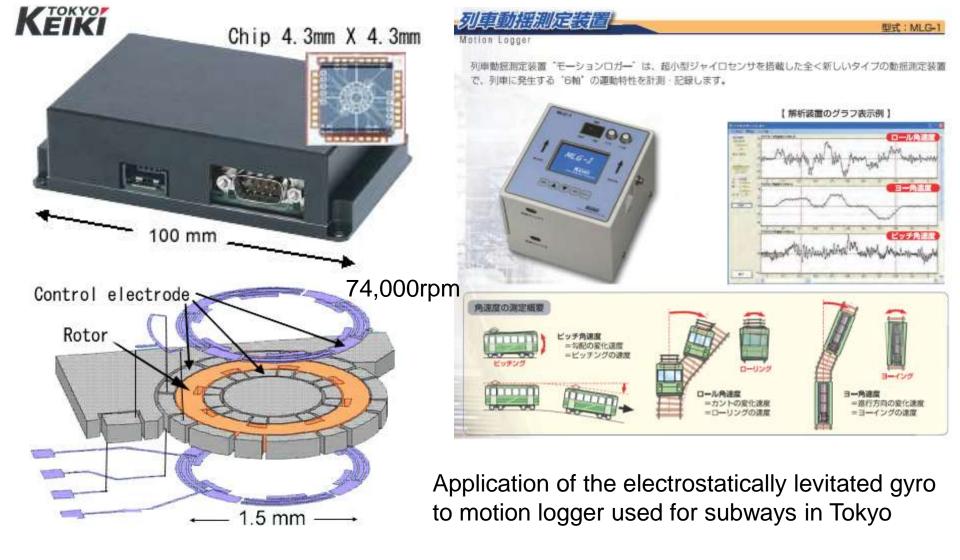
Resonating gyroscope (yaw rate sensor) and accelerometer for vehicle stability control

(M.Nagao et.al., SAE World Congress, Detroit, (2004) 2004-01-1113)

4µm

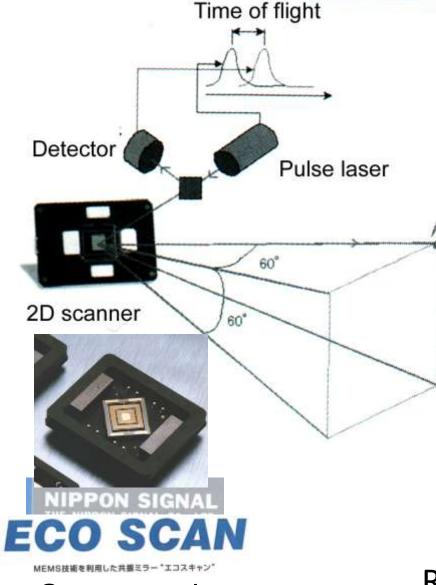


(M.Takinami, 11th Sensor Symposium, (1992) p.15)



Electrostatically levitated rotational gyroscope (Simultaneous measurement of 2 axes rotation and 3 axes acceleration)

(T.Murakoshi et.al. : Jpn. J. Appli. Phys., 42, Part1 No.4B (2003) p.2468)

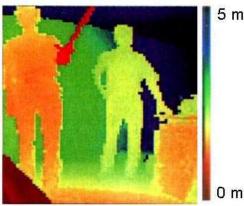


2D Optical scanner

(N.Asada et.al., IEEE Trans. on Magnetics, 30 (1994) 4647)



Ebisu station (platform doors using the ranging imager)

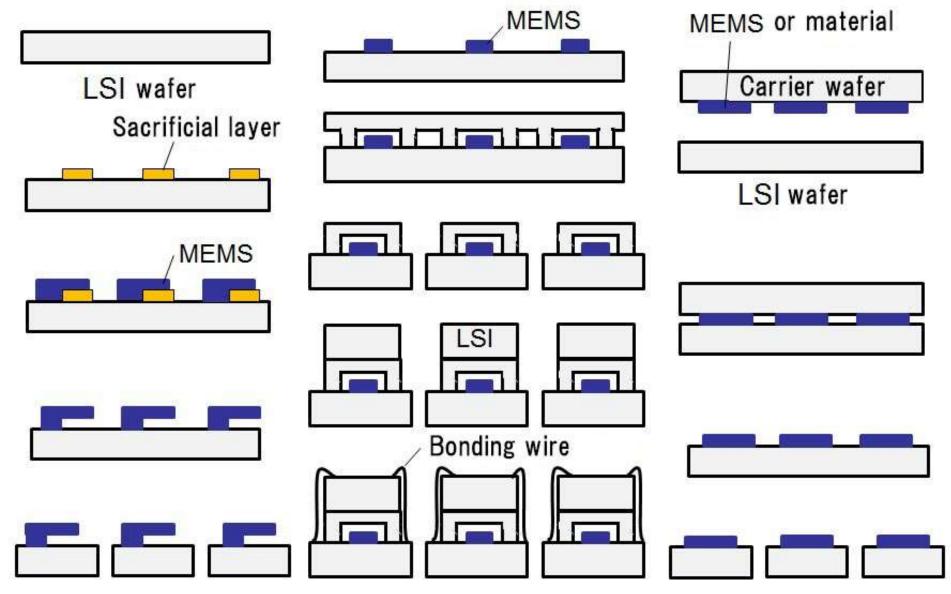


5 m

Color correspond to the distance

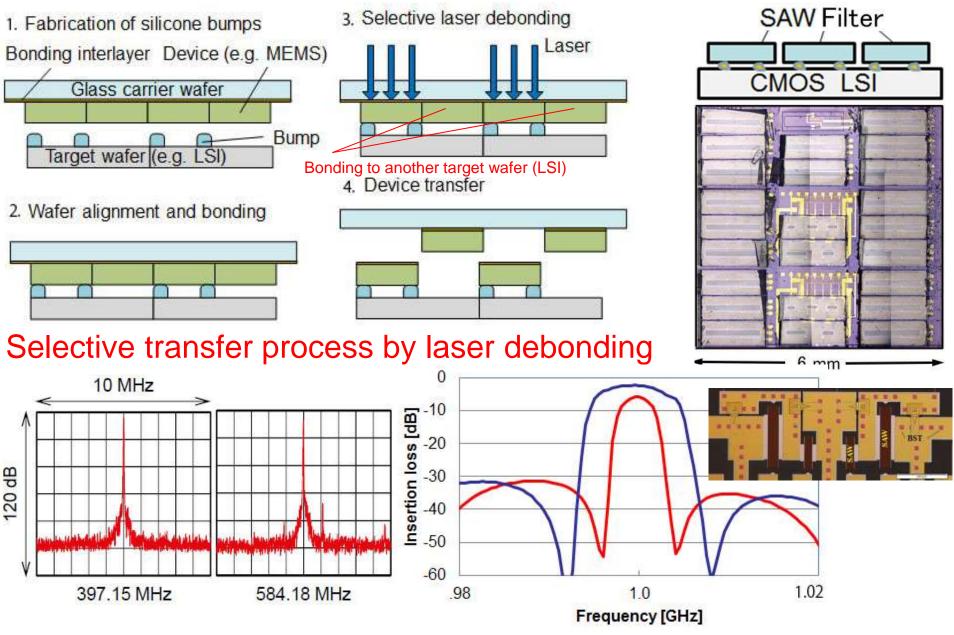
Ranging imager for safety systems and other applications

(T.Ishikawa, H.Inomata : Japan Signal Technical Report, 33, 1 (2009) 41)



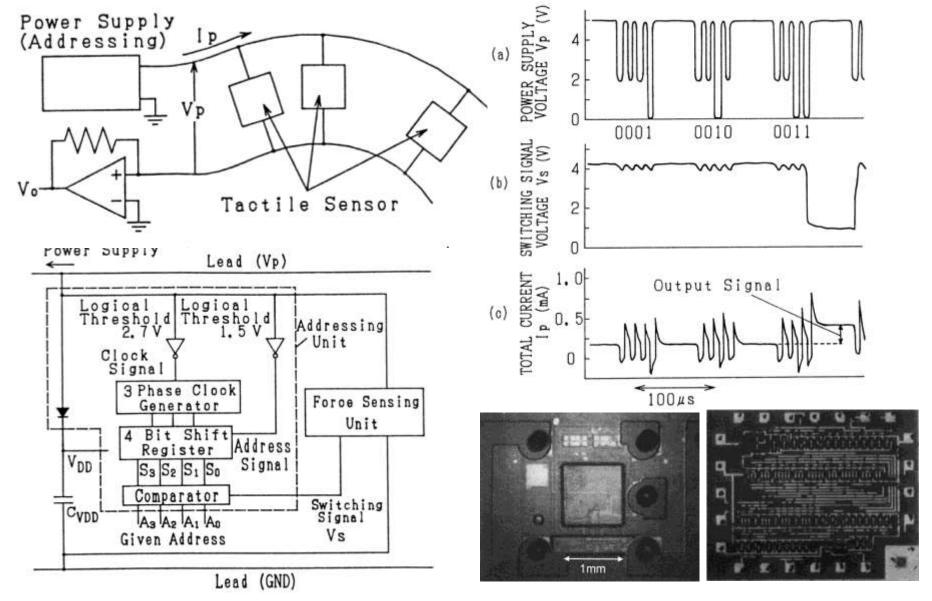
(a) Surface micromachining (b) Assembly of packaged MEMS (c) Transfer of MEMS on LSI (Limitation of MEMS process) and LSI (Limitation in interconnection) (no limitation)

Hetero integration



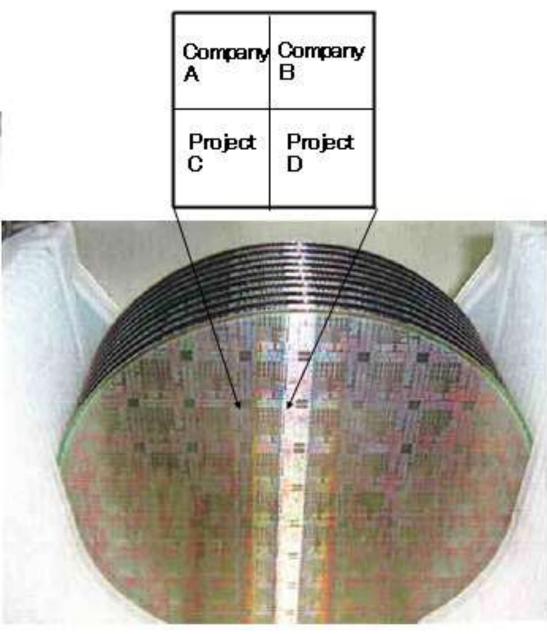
Multi SAW filters on LSI Tunable SAW filter using ferroelectric varactor

(S.Tanaka, M.Yoshida, H.Hirano, M.Esashi, 2012 IEEE Internl. Ultrasonics Symp. (2012) 1047). ³⁴



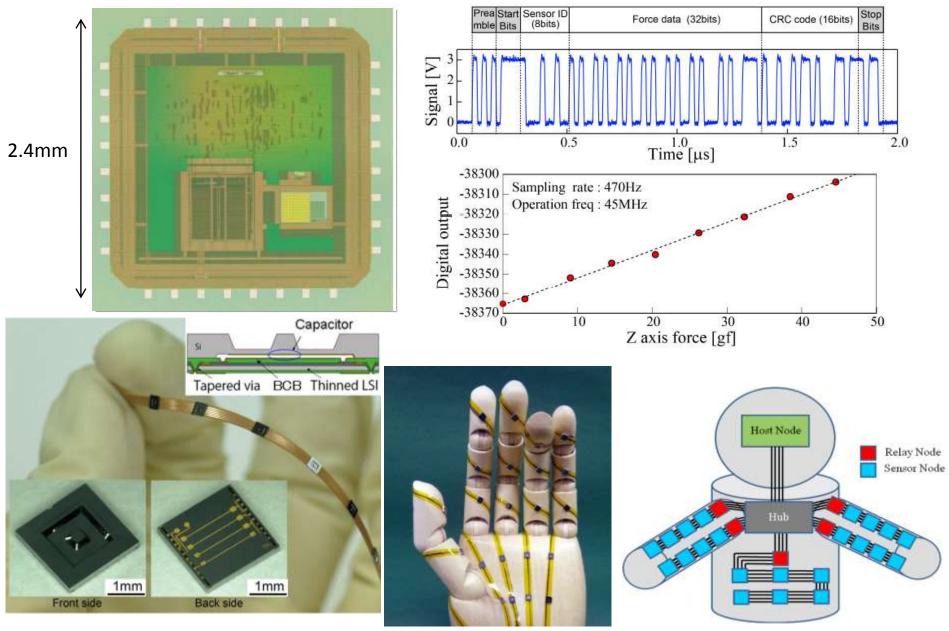
(1,000 Tr./chip in our lab., 1,000,000 Tr./chip in company, 10,000,000,000 Tr/chp now)

Common 2 wires tactile sensor array (polling type) 35 (S.Kobayashi & M.Esashi, Technical Digest of the 9th Sensor Symposium,(1990),137)



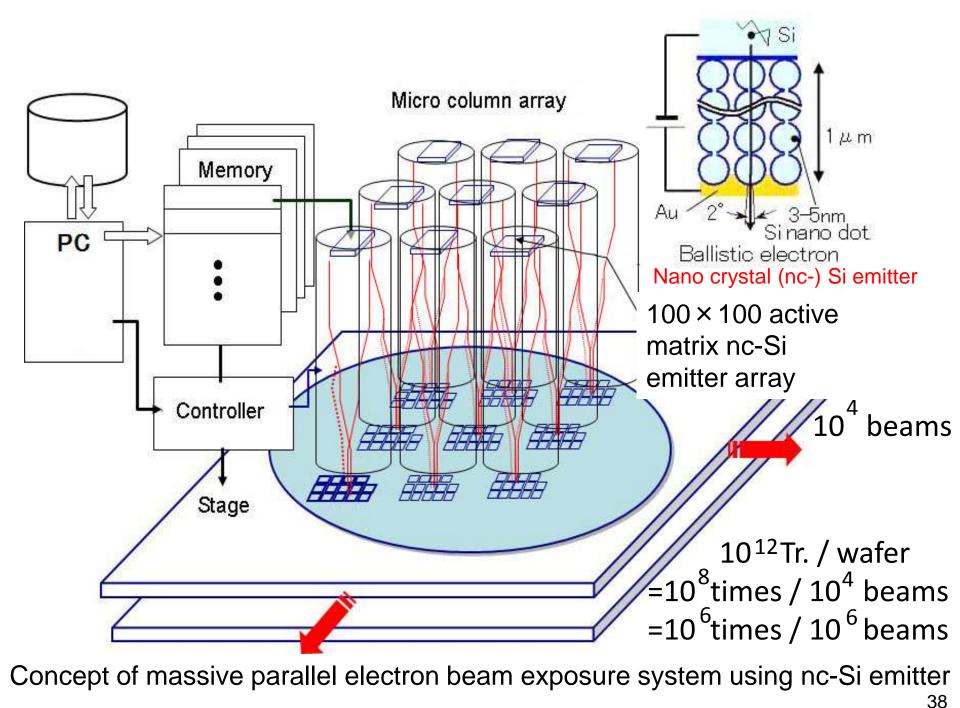
Ricoh, Toyota motor, Pioneer, Nippon signal, Toppan TDC, Kitagawa iron works, Sumitomo precision, NIDEC COPAL elec. Nikko, Toyota central R&D lab, Nippon dempa kogyo, Japan aviation elect. Ind., MEMS core, MEMSAS, Furukawa Electric, Denso Laboratories in Tohoku Univ.

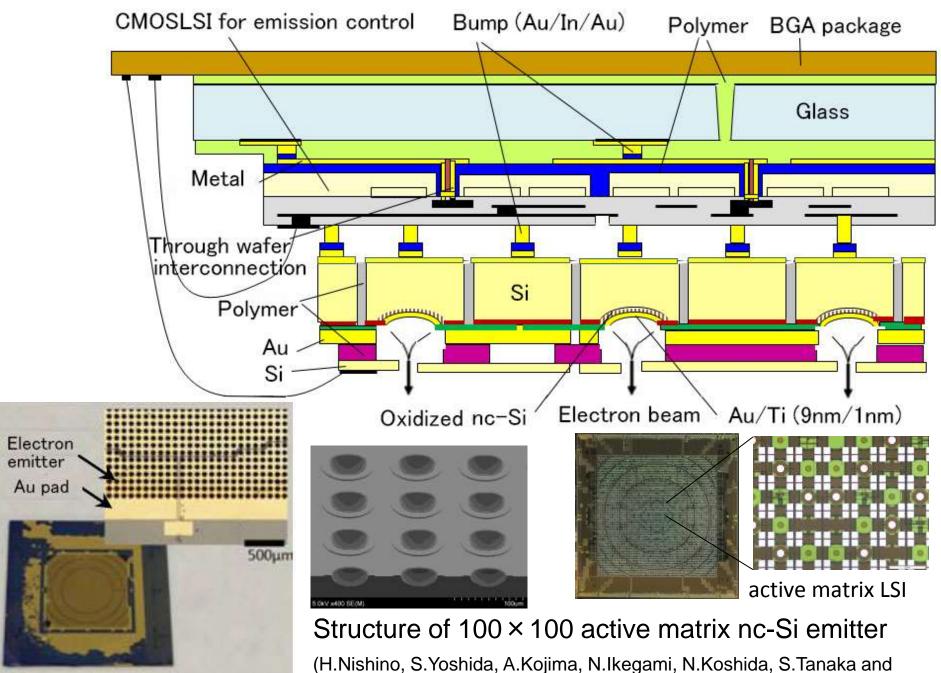
Shared CMOS LSI wafer



Tactile sensor network for robot (event driven type) (M.Muroyama, M.Makihata, M.Esashi et al., Smart Systems Integration (SSI) 2014, (2014))

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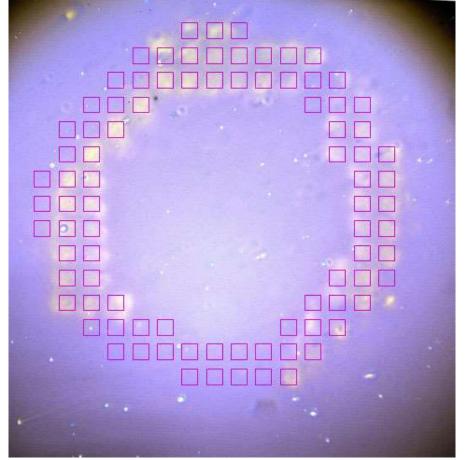


10mm

M.Esashi, Technical Digest IEEE MEMS 2014 (2014) 467-470)



Experimental setup for 1/100 and 1/1 exposure test.



Exposed patter on a resist using 1:1 projection system with 15 × 15 planer type nc-Si 40electron source (Electron source pattern is superimposed in the right photograph)

(N.Koshida et al., SPIE Advanced Lithography, San Jose, 2015/2/25)

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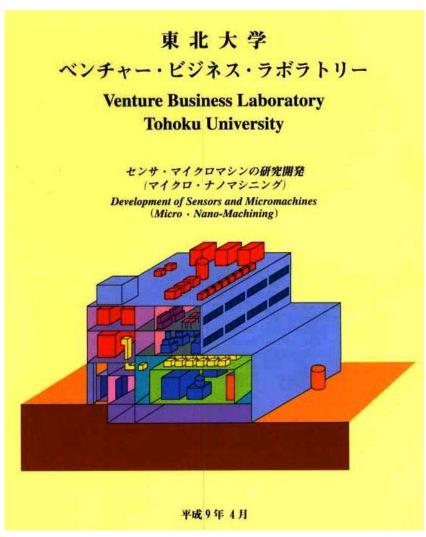
Summary



Instructions are directly written on the panel to prevent wrong usage

Shared facility (Micromachining room) in the building of Electrical group proposed by Esashi and Niitsuma (research associate) in 1980.

Auger electron spectroscopy bought by grant-in aid for scientific research and equipments for mask making, assembly etc. were commonly used. Accumulation of knowhow for the common use



Micro / Nanomachining Research & Education Center (MNC) (2007-) (Director Prof.S.Tanaka)

Venture Business Laboratory (VBL)(1997-2006)





Clean room for 2 inch process (600m²)

ベンチャーラボ利用の皆様へ

Message to VBL users

Director M.Esashi1998.2.6

ベンチャーラボを利用して頂いている皆様へ、私がどのような考えで運営していき たいかということをご理解いただき是非協力をお願いしたい・・・・・

内部的な調整にエネルギを費やし自己満足しているような状態でなく、効率を上げ て外部に役立つ研究成果を生み出していける・・・

第一は、ユーザの立場になって利用法を決めるということです。多くの場合に管理 の都合からルールを決めるために無駄が多くなっています。例えば講習会を受け た利用者しか使えないとか、何週間か前に申し込むことなどということです。実際の 研究では先の見通しなどは立たないもので、急に使う必要が生じるものです。装置 を使っている時に一緒について使い方を習ってもらうことにしました。教える人はで きるだけ詳細にまで教えてほしい。面倒なので代わりにやってあげるということにな りがちですが、メンテナンスなども含めてついていてもらい、その人に手伝ってもらう つもりでやって下さい。

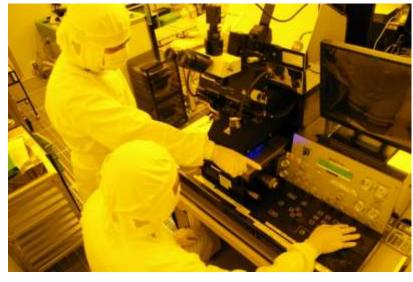
<u>装置の維持は最も使う人(研究室)にやって頂きます</u>。受益者負担の考え方に立ち、 できるだけ負荷を分散し、皆様が自分の研究をできるようにと考えています。

第二は、いかにすれば自主性を保ち・・・

第三は、透明で開放的にし、情報へ効率よくアクセス・・・

User should learn not only the operation but also maintenance from the person who is using the equipment.

The management and maintenance of equipment should be done by the person (laboratory) who uses it most frequently (not by the owner laboratory) etc. 44

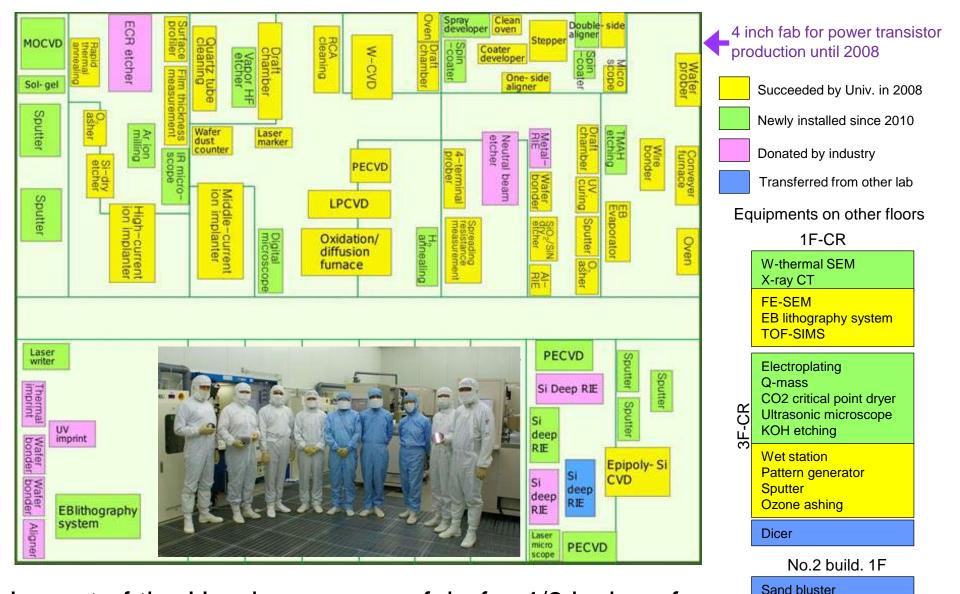






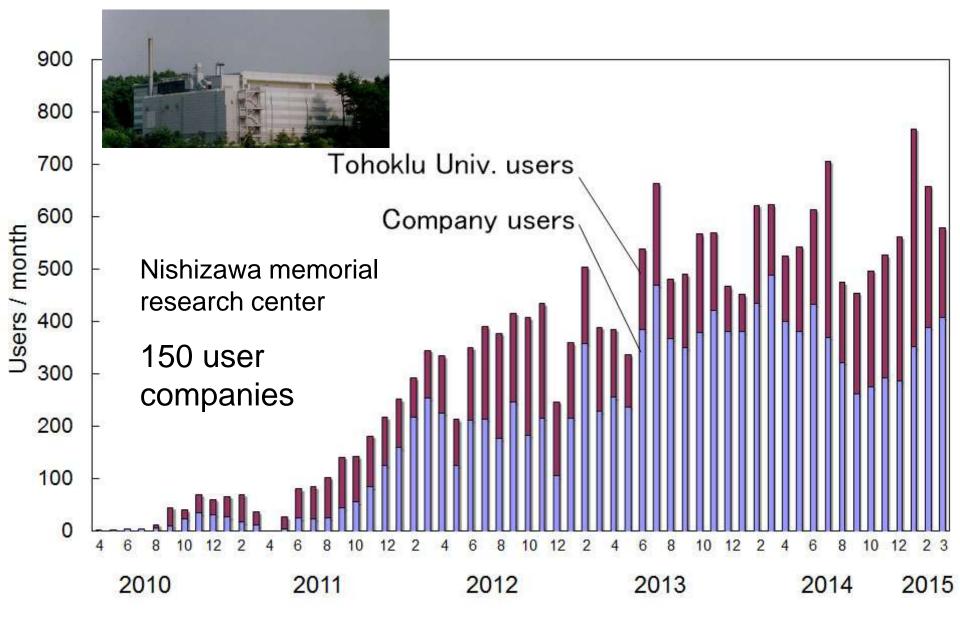
Companies which can not prepare their own facility dispatch their employees to operate equipments by themselves for development and small volume production.

Shared facility for industry to prototype MEMS devices (4 / 6 inch) Hands-on-access fab. (Nishizawa memorial research center in Tohoku Univ.) Contact person : Assoc. Prof. Kentaro Totsu totsu@mems.mech.tohoku.ac.jp 45

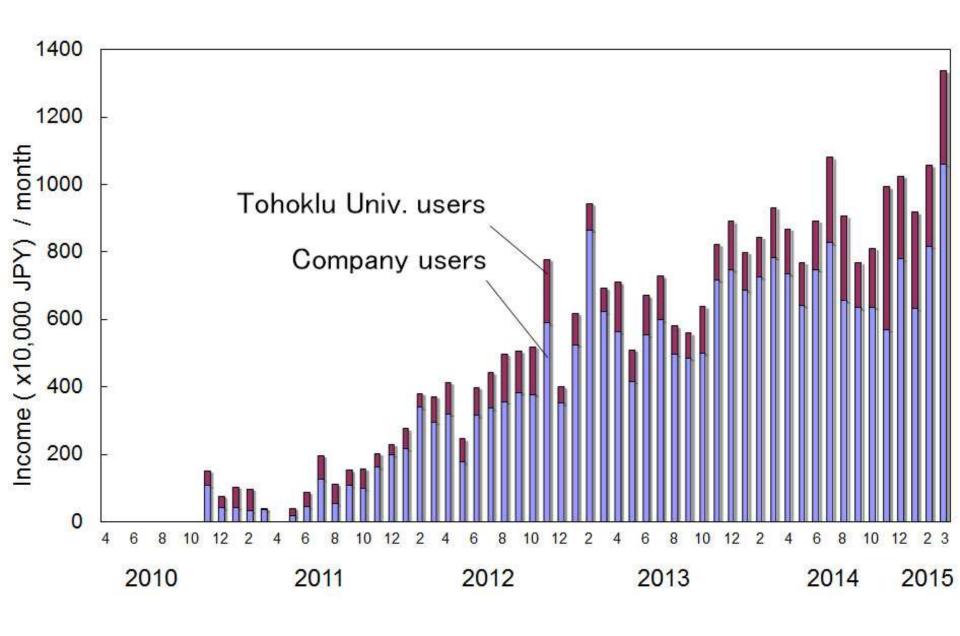


Layout of the Hands-on access fab. for 4/6 inch wafer

Companies are allowed to sell MEMS devices produced in the "Hands-on-access fab." (2013/7 ~)



Users of the Hands-on-access fab.



Income of the Hands-on-access fab.

MEMS Park Consortium (MEMSPC)

MEMS core Co.Ltd. (Contract development)

Nishizawa center, (Tohoku Univ.) (Hands-on access fab.)

(Initial stage prototyping)

Micro System Integration Center (µSIC), Tohoku Univ. Advantest component Co.Ltd. (Contract production)

AIST (Tsukuba) (Production stage prototyping)







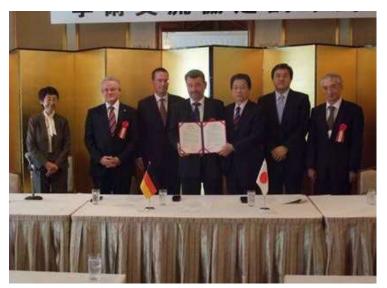
Experiences of MEMS IC research and construction of common facility

- 1. Chemical sensor & prototyping facility(graduate student) (1970-1975)
- 2. Biomedical micro sensors (Research Associate) (1976-Sept.1981)
- 3. Development of custom CMOS IC (Assoc. Professor) (Oct.1981-1990)
- 4. Integrated MEMS & industrialization (Professor) (1991-)
- **Open collaboration**
- 5. Common facility for prototyping
- 6. Accumulation and utilization of knowledge
- 7. Supporting industry
- 8. Education for students who are eager to be useful

Summary



FhG Germany – Sendai city partnership signing ceremony in Munich (July15,2005)



FhG Germany – WPI-AIMR Tohoku Univ. partnership signing ceremony in Sendai (Nov. 8, 2011)



1st Fraunhofer Symposium in Sendai
"Doing Worldwide Business via MEMS technology" (Oct.19, 2005)
10st Fraunhofer Symposium in Sendai (Nov.26, 2014)

FhG Project center in WPI-AIMR, Tohoku Univ. (April 1, 2012)

51

Collaboration with FhG (Fraunhofer Institute) in Germany

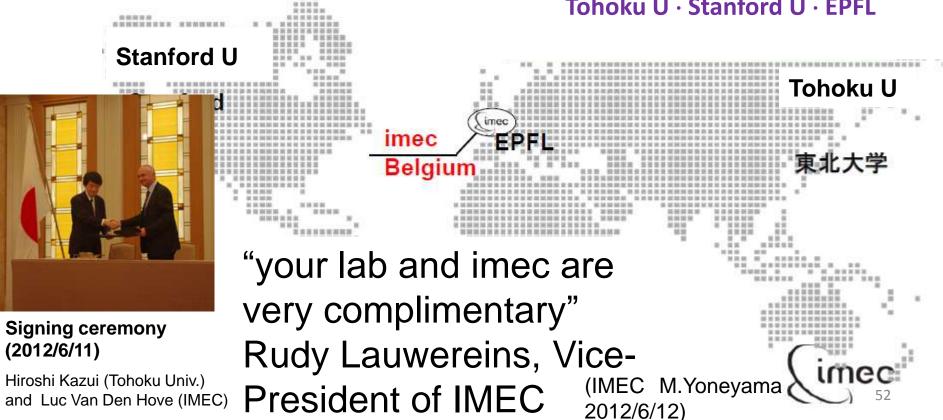


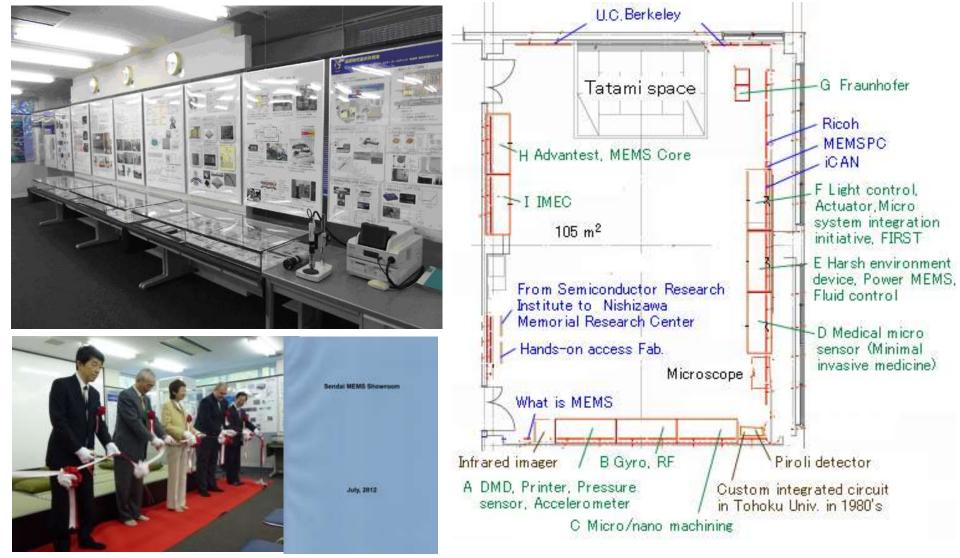






2013/11/8 Seminar in Sendai 2014/11/12 Seminar at IMEC Strategic Partner Tohoku U · Stanford U · EPFL





Catalog

Efficient way to access accumulated knowledge is important for heterogeneous integration

Sendai MEMS showroom (2012/5/16 renewal opening) http://www.mu-sic.tohoku.ac.jp/showroom/index.html (Japanese)

http://www.mu-sic.tohoku.ac.jp/showroom_e/index.html (English)

Efficient development for heterogeneous integration

Information from universities

(MEMS park consortium <u>http://www.memspc.jp</u>) Free MEMS Seminar in Tokyo (Aug. 23-25, 2006) 280 attendees Free MEMS Seminar in Sendai (Aug. 22-24, 2007) 75 attendees Free MEMS Seminar in Fukuoka (Aug.20-22, 2008) 150 attendees Free MEMS Seminar in Nagoya (Aug.4-6, 2009) 100 attendees Free MEMS Seminar in Tsukuba (Aug.5-7, 2010) 211 attendees Free MEMS Seminar in Kyoto (Aug.9-11, 2011) 175 attendees Free MEMS Seminar in Tokyo (Aug.22-24, 2012) 226 attendees Free MEMS Seminar in Tsukuba Univ.(Aug.7-9,2 013) 110 attendees Free MEMS Seminar in Osaka (Aug.5-7, 2014) 140 attendees Free MEMS Seminar in Toyohashi U.T. (Aug.5-7, 2015)

High-tech. small volume production

Efficient utilization of facilities MEMS seminar





Experiences of MEMS IC research and construction of common facility

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Summary

In the past

Company		Univer	University		
At present Company	Foreign companies	Government researcl			
In future					
Company	/ Governme	University nt research institutes			
Application Facility for prototyping Bas					
Rohm \leftarrow Kionics (Murata manufacturin TDK \leftarrow EPCOS (G Megachips \leftarrow SiTin Alps \leftarrow Qualtre (US Sharp \leftarrow Pixtronix	ng ← [¯] VTI (Fii ermany) [RF o ne (USA) [ME SA) [Bulk acou	nland) [Acceleror components] MS oscillator] ustic gyro]	neter] 56		

MEMS Park Consortium (MEMSPC)

Nishizawa center, (Tohoku Univ.) (Hands-on access fab.)

(Initial stage prototyping)

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Advantest component Co.Ltd. (Contract production)

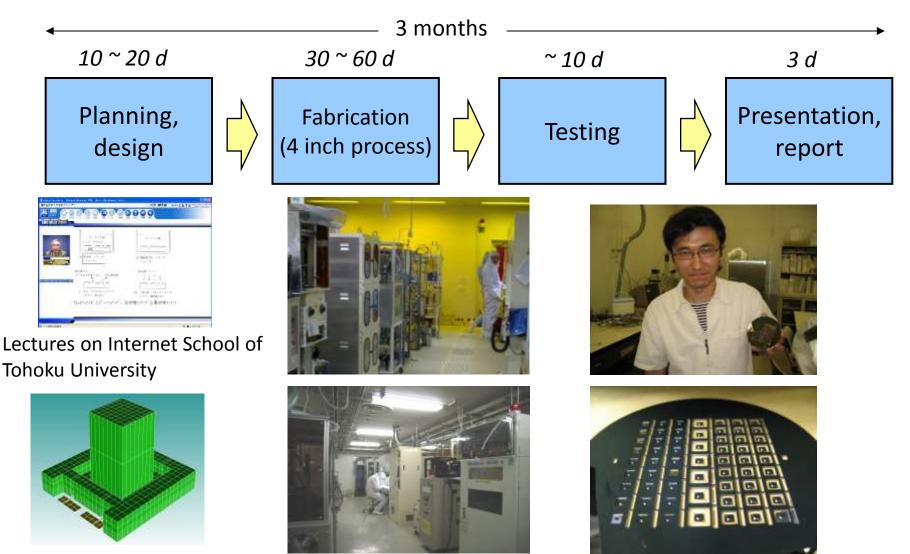
AIST (Tsukuba) (Production stage prototyping)



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Design

Training of Fabrication

Ex. Capacitive 3-axis accelerometer MEMS Training Program in Sendai MEMS park consortium Since Apr.2007. Fee 1 million yen. Trainee participate with own subject. 15 companies participated.



High-Frequency, Low Power Consumption MEMS Relay

Advantest's high-frequency MEMS relay utilizes piezoelectric actuation to achieve low power consumption and high reliability. Via Advantest's proprietary deposition technology, the relay features a piezoelectric film only 1 micron thick, making low actuation voltage possible. The relay also has high reliability, using contact-point control technology honed in Advantest's semiconductor testing equipment, and it can handle up to 20 GHz high-frequency transmission, using Advantest's high-frequency measurement technology.

MEMS Relay Applications



Semiconductor Testing Equipment, High-Speed Communications Devices, High-Frequency Measurement Equipment

MEMS Relay Production Process 1st Step Si Wafer Actuation **RF MEMS Switches Unit Production** RF MEMS switches are mainly manufactured by these three steps 2nd Step **3rd Step** Wafer Gluing Cutting Si wafer actuation unit (2nd layer) including bimorph cantilever 1st Step **Glass Wafer Contact Portion Production** Gluing of three stacked wafers, MEMS switch cut including 3rd layer glass wafers from three layer wafer for casing **Glass wafer contact portion** (2nd layer) glass with embedded metal

59

Applied technology	Next generation wireless group	Wireless sensor sensor group	Optical microsystem	BioMedical Microsystem	
Basket Basic technology for LSI-MEMS integration Process Equipment Test and evaluation Design Material Packaging	wireless system	Ultra-Sensitive	tem group	osystem group	Fabrication Test Equipment group

Shared IP managed in the Patent Basket

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2005/7/19 Nihon Keizai Shinbun (first page)

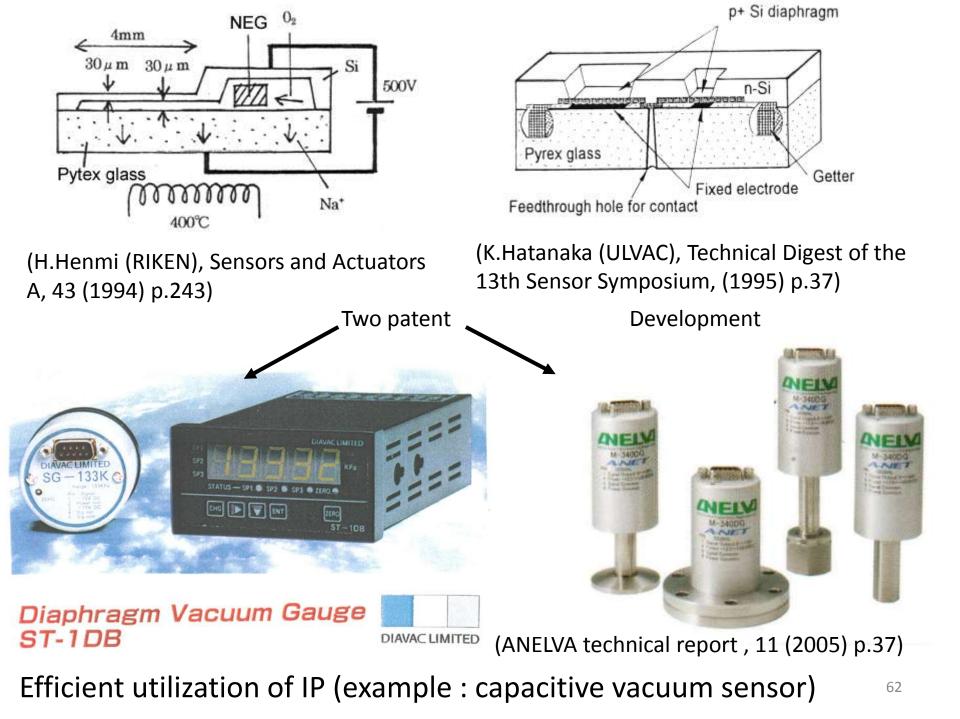
^{第1部} 東北大での反乱に見る ボタンの掛け違い

米国に遅れること20年、日本も大学の研究成果を産業界に応用しようと動き始めた。 数字上は盛り上がる産学連携もその実情は遅沌としている。 独立行政法人化をキッカケに知的財産力の強化を図る大学が権利主張をするあまり、 産業界との関係がぎくしゃくした例がそこかしこに見られる。 特許をめぐる企業と大学の考え方の相違が混乱の要因となっている。 今こそ企業はボートフォリオを示し、大学は特許を理解する時である。 産業界と大学が腹を割って語り合うところから産学連携の成功事例が生まれるだろう。 Nikkei Electronics (2005.1.31) 民間等共同研究員または受託研究員(以下、企業 派遣研究員)が、本学の研究実施場所で本学の指 揮管理を受けて発明を行ったときは、その発明は

原則として本学に帰属させることを定めました。

Patent by dispatched researcher was owned by Tohoku University (before revolution) (Our laboratory) Patent shared with company is paid by company. Exclusive license is given to the company but opened if not commercialized.

Revolution against IP rules in Tohoku University



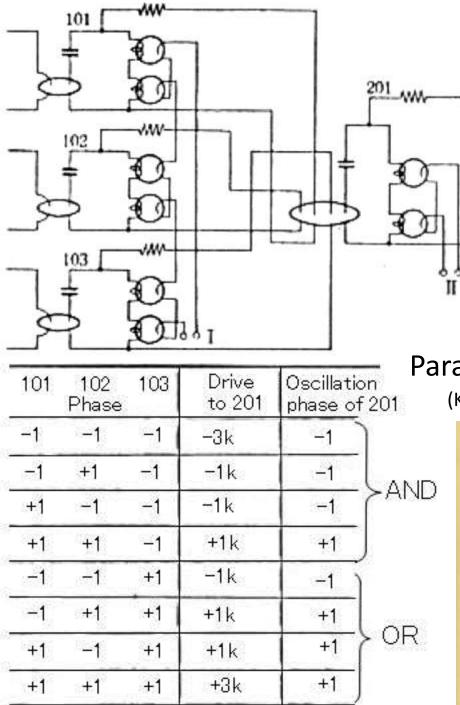
Experiences of MEMS IC research and construction of common facility

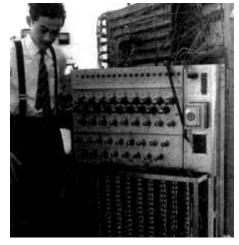
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Summary





E.Gotoh : Inventor of Parametron computer (Graduate student in the Univ. of Tokyo in those days)

Parametron computer

甲甙 24 年度

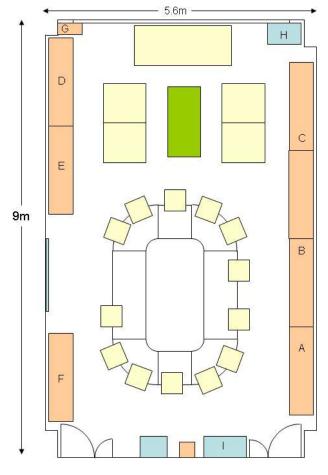
近代技術更学

圣公圣林和赵学家等级安排和

江列 正調

(K.Nagamori, Electronics (1958, March) p.918)

History of technology





A1 Electrical measurement : Potentiometer, Galvanometer
A2 Wired communication : Microphone, Headphone
A3 Wireless communication : Vacuum tube and transistor radio
B1 Recording : phonograph (Edison), Vacuum tube magnetic
tape recorder

B2 Computer : Mechanical computer, calculator

C1 Vacuum tube : Various vacuum tubes, Vacuum tubes for take-out, Manuals

C2 Transistor • IC : From vacuum tube to transistor and LSI C3 Haggerty's forecast (1964)

D1 Optical Instruments (1) optical measurement : Microscope, Radiation thermometer, D2 Optical Instruments(2) camera : Analog recording camera, 8mm movie

E1 Hobby : Mechanical doll, Aibo, Micro flying robotand computer controlled model car

E2 Automobile : Model T Ford, Model A Fordmanual etc.

F1Measure gause : Balance, Thermometer, Hygrometer

F2 Clock : Pendant camera, motor camera, tuning-fork camera

- F3 Typewriter : Portable typewriter
- H Probe card by Kiyota
- G Books on the history of technology
- I Materials related to Tohoku Univ. and companies

Historical Museum of Technology

http://www.mu-sic.tohoku.ac.jp/museum/



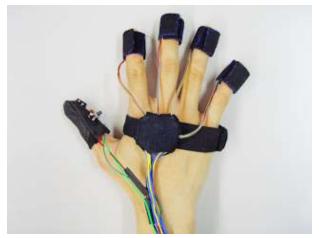


Yomiuri shinbun, Feb.20, 2009



Ford Model T (donated by Mr.T.Tawara (Optoelectronics))





TEMS (Talking Equipment from Manual Sign) iCAN'11 winner, Kyoto Univ.





5th International Contest of Application in Nano / micro technologies (iCAN'14) July 20, 2014 in Sendai (for high school and university students)



TU DARMSTADT, Germany SMART PROTECTION GOGGLES



Fukushima prefectural Koriyama-kita technical high school, Japan Pro ROBO -Robot to protect the safety of family

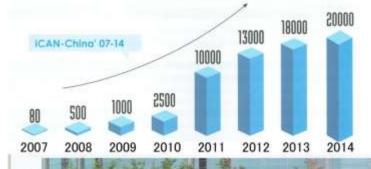


At the Institute of Electromechanical Design at TU Darmstadt smart protection goggles were developed to increase the safety at workplaces where the use of goggles is mandatory. The goggles detect when they are properly worn and send this information to a wireless receiver. This signal is used for different applications, for example to toggle a warning light thus alarming the user.



iCAN History

- iCAN-China'07-14 / 07, Shanghai / 08, Shenzhen / 09, Haerbin / 10-14, Wuxi
- P iCAN'10 / Xiamen, China / 2010.1.20-22
- ICAN'11 / Beijing, China / 2011.6.5-7
- P ICAN'12 / Beijing, China / 2012.7.6-9
- CAN'13 / Barcelona, Spain / 2013.6.16-18
- ICAN'14 / Sendai, Japan / 2014.7.19-21
- CAN'15 / Alaska, USA / 2015.6.21-25



20,000 attendee in the China domestic contest in 2014

2015

Summary

 Common facility with versatile equipments and its effective utilization. Slim equipments made in-house for easy maintenance.

 Accumulation and reconstruction of knowledge from the past to the latest. Provide high quality knowledge delivery services.

 Answering to the needs and educating ourselves by studying heterogeneous knowledge and culture (international, different sectors etc.), Successful experience of practical contribution motivates us.

- Do not depend on outsourcing just for shortcut. Real experiences rather than virtual ones.
- Good subjects, effective advices and environment for enabling for student.
 Don't compare students.

• Think from basic. How useful outputs are is more important than the number of papers. Achieve results with minimum expense using second hand equipments. Patent is to protect products. Collaborative rather than competitive.

